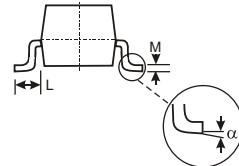
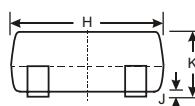
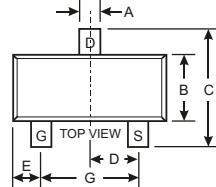


Features

- Advanced trench process technology.
- High Density Cell Design For Ultra Low On-Resistance.
- Fully Characterized Avalanche Voltage and Current.
- Improved Shoot-Through FOM.
- We declare that the material of product compliance with RoHS requirements.



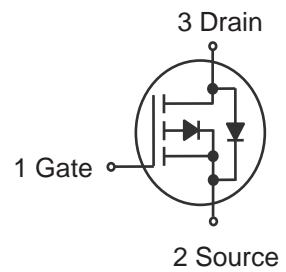
SOT-23		
Dim	Min	Max
A	0.37	0.51
B	1.20	1.40
C	2.30	2.50
D	0.89	1.03
E	0.45	0.60
G	1.78	2.05
H	2.80	3.00
J	0.013	0.10
K	0.903	1.10
L	0.45	0.61
M	0.085	0.180
α	0°	8°
All Dimensions in mm		

APPLICATIONS

- TrenchFET Power MOSFET.
- Load Switch for Portable Devices.
- DC/DC Converter.
- Marking Code: S5 OR A5SHB.

Maximum Ratings @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 12	V
Drain Current	I_D	-4.4	A
Pulsed Drain Current (10 μs Pulse Width)	I_{DM}	-20	A
Maximum Power Dissipation	P_{tot}	0.96	W
Thermal Resistance from Junction to Ambient (PCB mounted) ¹⁾	$R_{\theta JA}$	130	°C/W
Junction Temperature	T_J	150	°C
Storage Temperature Range	T_{stg}	-55 to +150	°C



¹⁾ 1 in² 2oz Cu PCB board.



HAICHUANG SEMI

HC2305

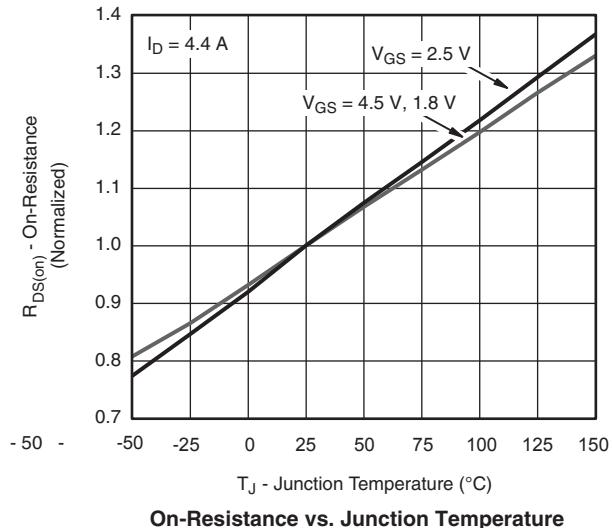
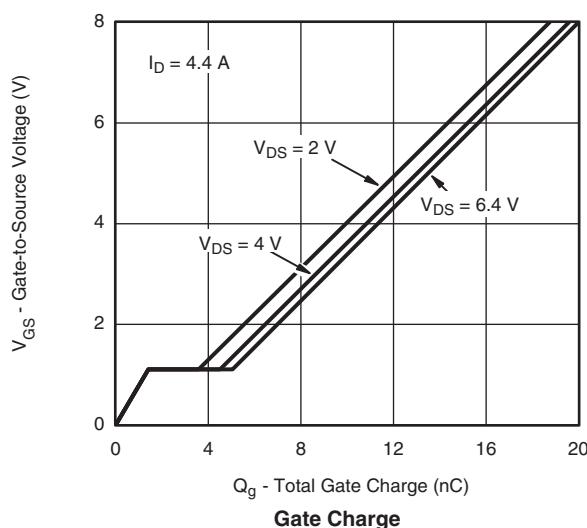
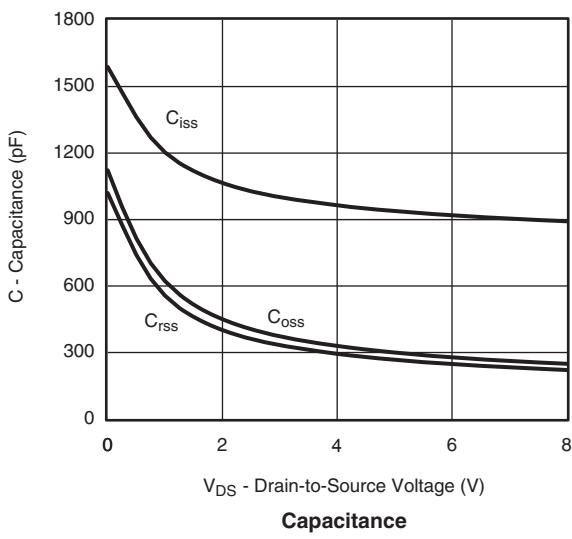
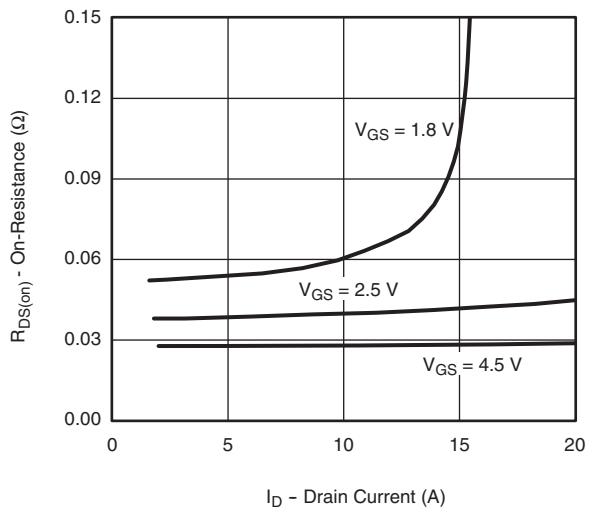
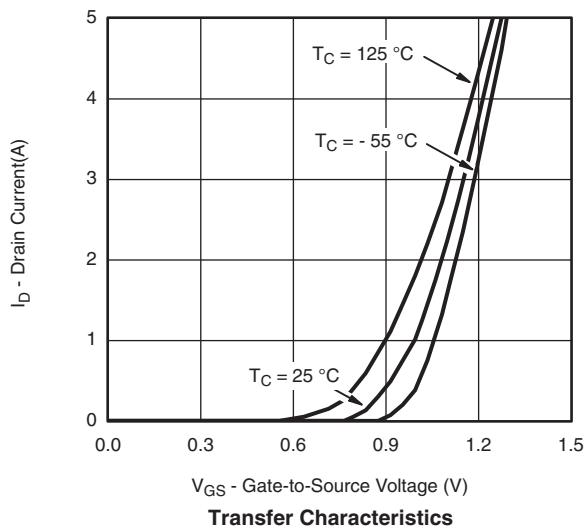
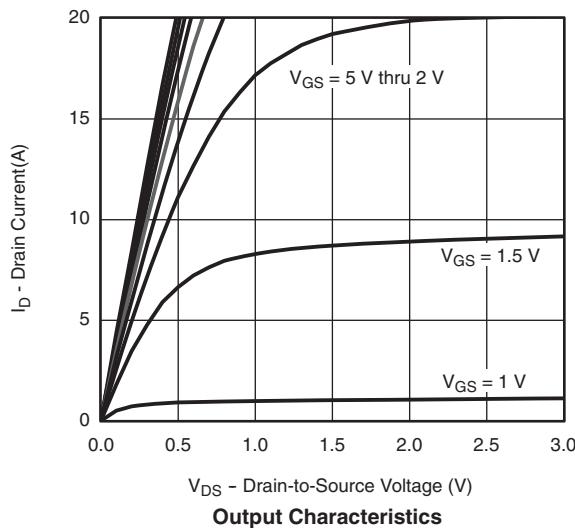
P-CHANNEL ENHANCEMENT MODE MOSFET

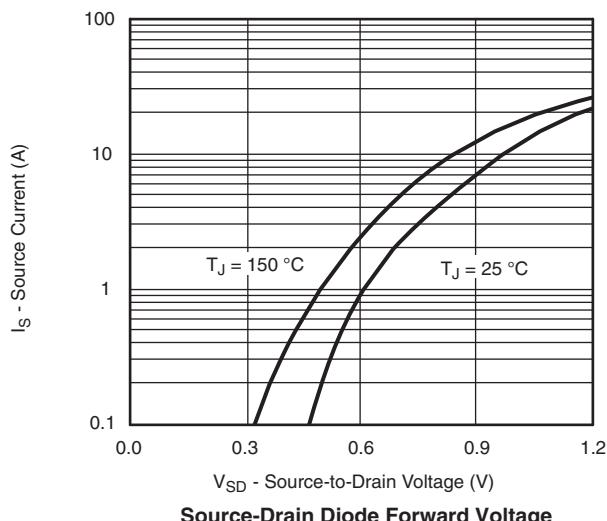
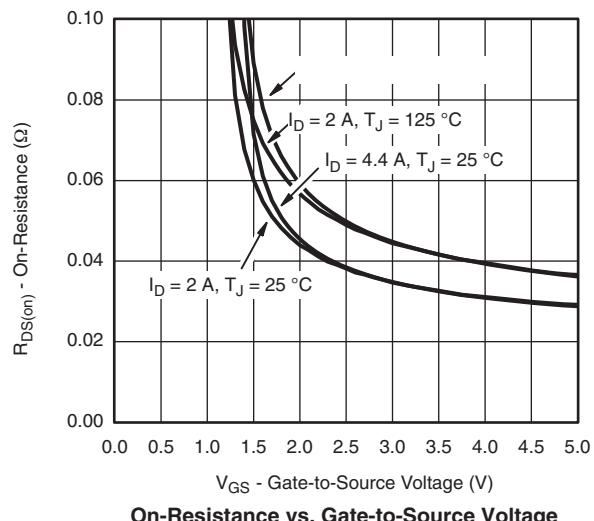
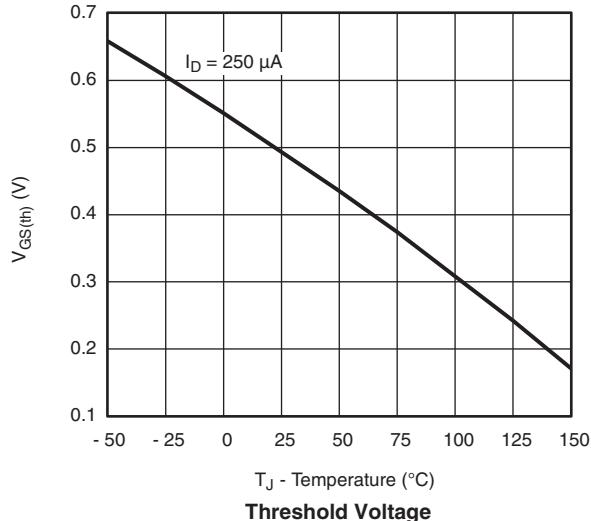
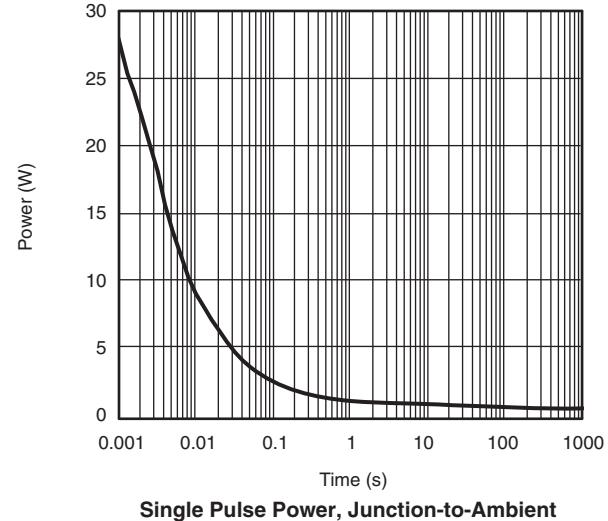
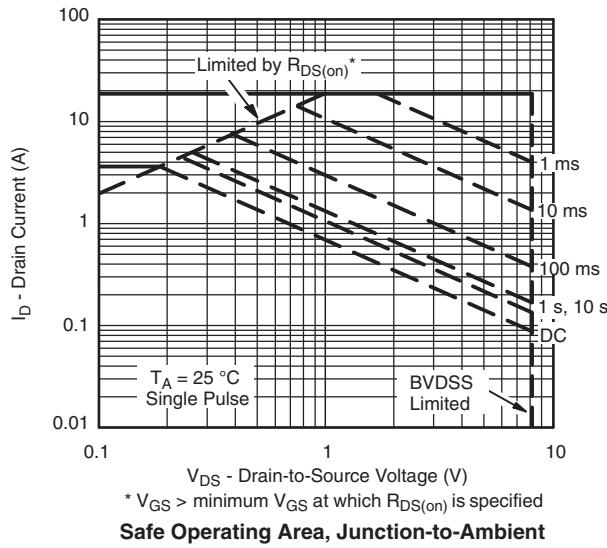
Electrical Characteristics @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Static						
Drain-source breakdown voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-20			V
Gate-source threshold voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.4	-0.65	-1.0	
Gate-source leakage	I_{GSS}	$V_{DS}=0V, V_{GS} = \pm 12V$			± 100	nA
Zero gate voltage drain current	I_{DSS}	$V_{DS}=-20V, V_{GS} = 0V$			-1	μA
Drain-source on-state resistance ^a	$R_{DS(\text{on})}$	$V_{GS} = -4.5V, I_D = -4.4\text{A}$		25	36	mΩ
		$V_{GS} = -2.5V, I_D = -3\text{A}$		35	50	
		$V_{GS} = -1.8V, I_D = -2.0\text{A}$		47	60	
Forward transconductance ^a	g_f	$V_{DS} = -5V, I_D = -4.4\text{A}$	6			S
Dynamic						
Input capacitance ^{b,c}	C_{iss}	$V_{DS} = -4V, V_{GS} = 0V, f = 1\text{MHz}$		960		pF
Output capacitance ^{b,c}	C_{oss}			330		
Reverse transfer capacitance ^{b,c}	C_{rss}			300		
Total gate charge ^b	Q_g	$V_{DS} = -4V, V_{GS} = -4.5V, I_D = -4.4\text{A}$		20	30	nC
		$V_{DS} = -4V, V_{GS} = -2.5V, I_D = -4.4\text{A}$		12	18	
Gate-source charge ^b	Q_{gs}			15		
Gate-drain charge ^b	Q_{gd}			3.1		
Gate resistance ^{b,c}	R_g	$f = 1\text{MHz}$	1	5.1	10.2	Ω
Turn-on delay time ^{b,c}	$t_{d(on)}$	$V_{DD} = -4V, R_L = 1.1\Omega, I_D \approx 3.5\text{A}, V_{GEN} = -4.5V, R_g = 1\Omega$		20	30	ns
Rise time ^{b,c}	t_r			20	30	
Turn-off Delay time ^{b,c}	$t_{d(off)}$			40	60	
Fall time ^{b,c}	t_f			10	15	
Turn-on delay time ^{b,c}	$t_{d(on)}$			10	15	
Rise time ^{b,c}	t_r	$V_{DD} = -4V, R_L = 1.2\Omega, I_D \approx 3.3\text{A}, V_{GEN} = -8V, R_g = 1\Omega$		10	15	
Turn-off delay time ^{b,c}	$t_{d(off)}$			35	55	
Fall time ^{b,c}	t_f			10	15	
Drain-source body diode characteristics						
Continuous source-drain diode current	I_S	$T_C = 25^\circ\text{C}$			-1.4	A
Pulse diode forward current ^a	I_{SM}				-20	
Body ciode voltage	V_{SD}	$I_F = -3.5\text{A}$			-1.2	V

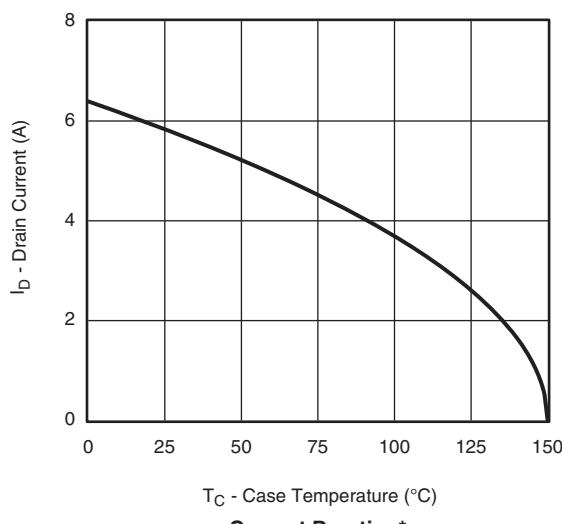
Note :

- a. Puls Test ; Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.
- c. These parameters have no way to verify.

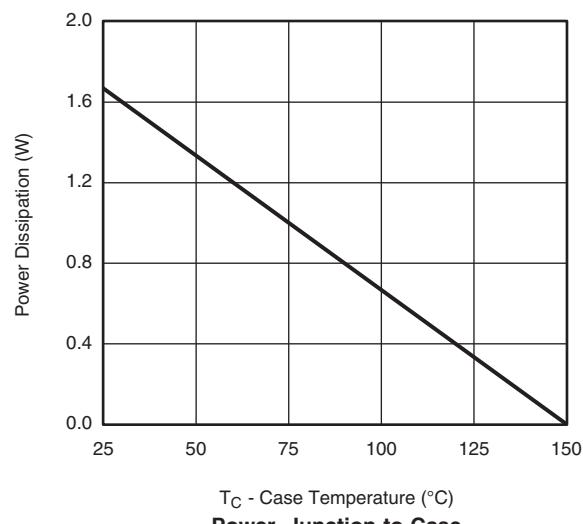
TYPICAL TRANSIENT CHARACTERISTICS


P-CHANNEL ENHANCEMENT MODE MOSFET
TYPICAL TRANSIENT CHARACTERISTICS

Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Threshold Voltage

Single Pulse Power, Junction-to-Ambient


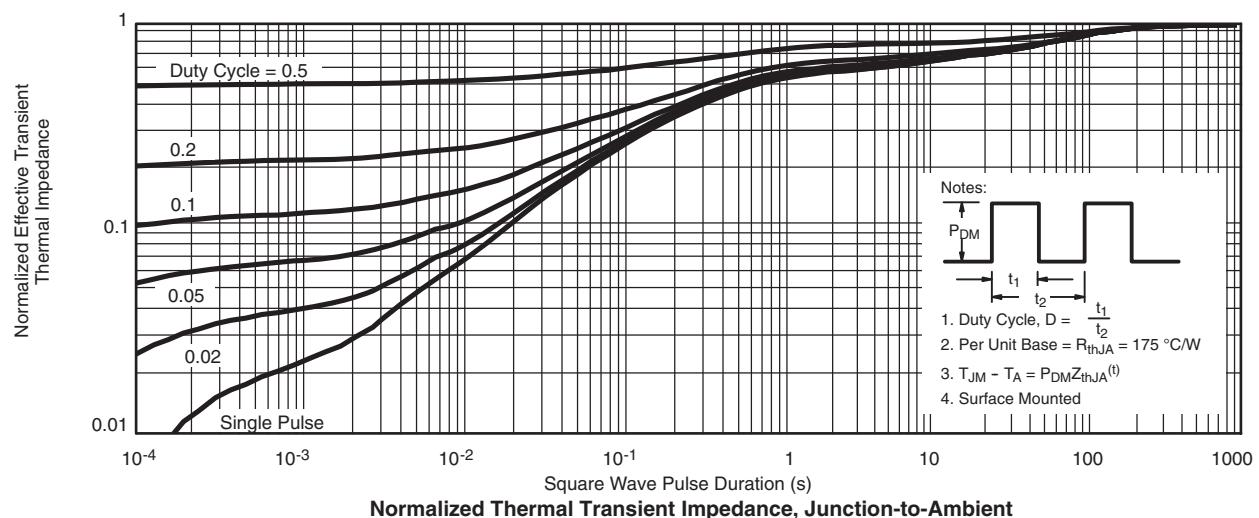
* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified
Safe Operating Area, Junction-to-Ambient

P-CHANNEL ENHANCEMENT MODE MOSFET
TYPICAL TRANSIENT CHARACTERISTICS


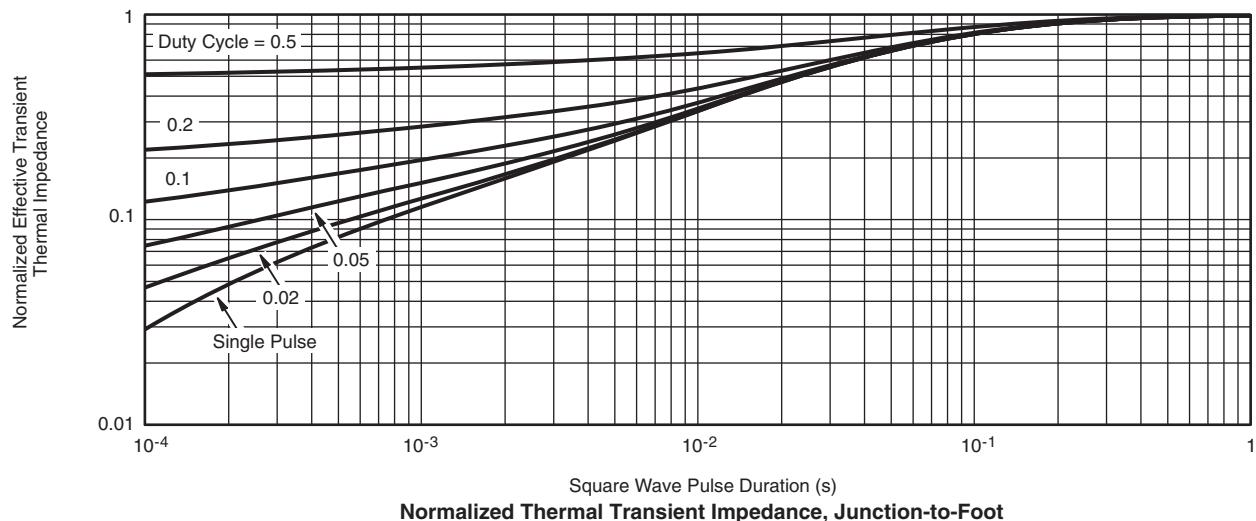
T_C - Case Temperature (°C)
Current Derating*



T_C - Case Temperature (°C)
Power, Junction-to-Case



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

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